

---

# *Packaging*

**Carol Livermore\***

**Massachusetts Institute of Technology**

**\*With thanks to Steve Senturia, from whose lecture notes some of these materials are adapted**

# Outline

---

- > **Evolution of the packaging dilemma**
- > **How to approach the challenge of getting a working system, including:**
  - **Packaging**
  - **Partitioning**
  - **Test**
  - **Calibration**
- > **Some common tools and considerations**
- > **Examples**

# Package requirements

---

- > **“Man the gates”**: let the right things in and out and prevent other things from entering or leaving
- > **Protect the die**
- > **Make it easy to interface the die with the rest of the world (outer layer of packaging must conform to industry expectations)**
- > **Be as inexpensive as possible**
- > **The details can vary greatly**
- > **Some elements that are often seen:**
  - **Fabrication/packaging cross-over, with first level packaging occurring at the wafer scale, in the fab**
  - **Die attach into a package**
  - **Die encapsulation**
  - **Making connections**
  - **The need to plan for calibration and test!**

# Evolution of the MEMS package challenge

---

- > **MEMS micromachining and packaging began as answers to a practical question: “If I want to take advantage of silicon piezoresistivity to measure pressure, what does the rest of the product look like?”**
- > **Subsequent products adapt what they can from the earlier approach and develop specific solutions where they must**
  - **Problem: no universal solutions**
  - **Must solve the details for every device design, and the solutions are almost always different**
- > **Enthusiasm for MEMS grows: packaging often neglected with painful results**
  - **High costs (package cost 10x device cost!), devices that must be redesigned**
  - **Devices can't make the jump to market!**
- > **Present drive to create more widely-applicable packaging solutions**

# A diversity of devices to package

---

Image removed due to copyright restrictions.  
Motorola accelerometer.

Image removed due to copyright restrictions.  
Ultrasonic transducer array made by Siemens Corporation.

Image removed due to copyright restrictions.  
Hymite/MEMSCAP packaged in-vivo magnetic switch.

Image removed due to copyright restrictions.  
Motorola manifold absolute pressure sensor.

# Outline

---

- > Evolution of the packaging dilemma
- > How to approach the challenge of getting a working system, including:
  - Packaging
  - Partitioning
  - Test
  - Calibration
- > Some common tools and considerations
- > Examples

# Key Ideas

---

## > Concurrent design

- *Design the device and the package at the same time*
- Often companies have different teams for the two parts...

## > Partition carefully

- Which functionalities go in the chips, and which functionalities go in the package?
- How many chips will it have?
- Which functionality goes on each chip?
- How will the chips be connected together, and to the package?
- How will the way we partition it affect the way that we have to test it?

# The question of electronics

---

## > Partitioning electronics and MEMS

- Ask yourself honestly if integrating electronic functionality monolithically with the MEMS device is worth it
- It is difficult to optimize two different things simultaneously
- Separating fab processes into pre-electronics and post-electronics can limit your options severely
- Two chips separately are often cheaper than one integrated chip (remember the  $N_{\text{masks}} * A_{\text{device}}$  rule?)
- A cute, monolithically integrated device that doesn't work because of unintended interactions between the MEMS function and the electronics is useless
- Some successful commercial products are monolithically integrated

# Designing for testability

---

- > If the device is expensive, the package is expensive, and the process of attaching the two is expensive, how much testing should you do before committing a device to a package?**
- > There is no universal answer to this question, but it must be considered for every device. Do a cost analysis with your best estimates of costs and yields to balance risk and cost.**
- > The package/test procedure will have a significant impact on the ultimate cost of building the part, and on its economic viability**
- > Many systems can't be tested at all without some form of packaging**

# Planning for variations

---

- > **Given the many variations possible from fabrication and packaging (both random and systematic), how do you ensure a working device at the end?**
- > **Aim for a perfect as-fabricated device and no shifts from the package?**
- > **Aim for a device that is perfect once it has interacted with the package?**
- > **Admit that you can't control all the factors and simply trim the hardware once it's packaged?**
- > **Admit that you can't control all the factors and simply calibrate whatever you get in the software?**
- > **All of these are expensive... do you want to put a lot of resources into getting the fab just right, or into fixing each and every part after it's made?**

# Checklist before detailed design

---

- > **You're ready to do the detailed design of the system and all of its components when you have the following:**
  - **Complete specifications for both the chip(s) and the package**
  - **Specifications for all interconnections**
  - **A list of all of the parasitics that you can think of, and some assessment of their effect on the system operation**
  - **Provision for calibration and test**

# To do list: the detailed design

---

## > For the MEMS device

- A process flow
- A mask set
- The corresponding device geometry and materials
- A model supporting predicted performance
- Specification of the test and calibration method

## > For the package

- Artwork
- Specification of components and how they are made (or where purchased)
- Acceptance procedures for packages

## > Full assembly

- The packaging procedure
  - Test, acceptance, and calibration
-

# Outline

---

- > **Evolution of the packaging dilemma**
- > **How to approach the challenge of getting a working system, including:**
  - **Packaging**
  - **Partitioning**
  - **Test**
  - **Calibration**
- > **Some common tools and considerations**
- > **Examples**

# Die separation

---

- > Multiple dies fabricated on the same wafer must be separated in order to be packaged and sold
  - > Die saw common
  - > Die saw blades are of order 30  $\mu\text{m}$  to 250  $\mu\text{m}$  thick
  - > High speed blade rotation, cooled by a flow of water
  - > Lots of debris, vibrations, and general dirt
  - > How to protect the device?
    - Release etch after die saw
    - Wafer bonding as first-level packaging, before the die saw step
    - Die saw the device upside down
    - Don't die saw: etch mostly through and crack chips apart
  - > Question: do you need to do any testing before you separate the dies?
-

# Die attach

---

- > **Whether IC's or MEMS devices, dies must be attached to a package**
- > **Package: application specific**
- > **Solder as adhesive: commonly soft solder (lower melting temperature, about 100 C – 400 C)**
- > **Epoxy as adhesive: cross-link when heated (about 50 –175 C)**
- > **Polyimide or silicone as adhesive**
- > **Adhesive application: dispense through a nozzle, screen print**
- > **Can use “pick and place” tools to position dies on top of adhesive in the package**

# Plastic packaging

---

- > **The integrated circuit standard**
  - > **Very inexpensive, pennies per electrical connection pin**
  - > **A thermosetting plastic is melted (ballpark 175 C) and injected into a mold**
  - > **The plastic cools and hardens**
  - > **The least expensive approach:**
    - **Attach the die to a metal lead frame with an adhesive**
    - **Injection mold the plastic around it**
    - **Question: will your device and electrical connections survive this?**
    - **Question: will encapsulation in plastic impair its functionality?**
-

# Plastic packaging

---

- > **Second approach: a more flexible, more expensive, gentler approach to plastic packaging**
- > **Injection mold the package around a lead frame before the die is attached**
- > **Attach the die with an adhesive**
- > **Cap the package**
- > **Applications:**
  - **Fragile devices or electrical connections**
  - **Achieving connections that are not standard in IC packages, such as fluid connections or optical transparency**
  - **Special requirements are integrated into the package cap**

# Ceramic packaging

---

- > Collections of particles are sintered at temperatures ranging from 800 C to 1600 C to form the package (often alumina,  $\text{Al}_2\text{O}_3$ )
- > Ceramic packages are often processed as laminates
  - Individual layers can have screen printed electric interconnects, metal film resistors, and even interlayer via connections
  - Anneal the package; braze pins to package
  - Make electrical connection between die and package
  - Cap and seal the package (application-specific)
  - Resistors on the outer layer can be trimmed after the die is packaged
- > Durable, potentially well-sealed (hermetic)
- > Higher cost (ballpark a few tens of dollars vs. less than a dollar)

# Metal packaging

---

- > **A solution for harsh environments or relatively quick prototyping**
  - > **Can be well-sealed (hermetic)**
  - > **Common materials: Kovar or stainless steel**
  - > **When features are more important than cost, can simply machine the package with the needed features**
  - > **Example: a pressure sensor for environments that silicon cannot tolerate**
    - **Package a Si pressure sensor in a stainless steel package**
    - **Cap the package in part with a thin stainless steel diaphragm**
    - **Fill the gap between Si and steel with oil to transfer the pressure**
-

# Making electrical connections

---

- > **Techniques adopted from IC packaging**
  - > **Wire bonding connects electrical contact pads on die to electrical contact pads in package**
    - **An ultrasonic sewing machine that stitches with wire**
    - **Heat + pressure + ultrasonic energy joins wire to contact pad**
    - **Frequency considerations: ultrasound may excite a resonance**
    - **Thickness of bond pads**
  - > **Flip-chip bonding**
    - **Chip turns upside down; solder bumps attach it directly to package**
    - **Heat to flow solder (think about temperature)**
    - **Smaller connections/lower inductance than with wirebonding**
-

# Making fluid connections

---

- > **Not standardized**
- > **Techniques at the laboratory scale**
  - **O-ring seals and conventional tubing**
  - **Glue a tube in a hole (includes more sophisticated approaches)**
  - **Stick a needle through a polymer structure, and inject through it**
- > **For lab-on-a-chip applications: various proposals for the “world to chip” interface**
- > **For a pressure sensor: protect the membrane with a cap layer and route a hole in the package to the connector of your choice (ie screw thread)**
- > **For your application...?**

# Packaging in the fab – why do it?

---

- > **Your structure will become so fragile when you do the release etch that you will no longer be able to package it**
  - > **Your device won't survive die saw unless the fragile parts are encapsulated**
  - > **You want to minimize the package size**
  - > **You can't afford to have any particulates on your device, so it needs to be encapsulated before it leaves the cleanroom**
  - > **It's less expensive in your case**
  - > **You expect the quality of the seal to be better in a microscale process such as anodic bonding than in a macroscale process such as gluing**
  - > **You want to create a sealed cavity with vacuum inside**
  - > **You want to create a sealed cavity with a controlled atmosphere inside**
-

# Sealing

---

## > Vacuum operation

- Device needs to operate at vacuum, or some fixed pressure, without ever being pumped out again
- Examples: measuring absolute pressure, high Q resonators
- Typically accomplished in the fabrication process rather than in packaging
- Approaches: wafer bonding, deposited films as sealants
- Concern: outgassing

## > Isolation from environment

## > Hermetic packaging

- Device doesn't need to operate at vacuum, but if water gets inside, the device will eventually be destroyed

# Vacuum sealing by anodic bonding

> Anodic bonding to seal a pressure sensor

> Fabricate on a Si wafer; dissolve it away at the end

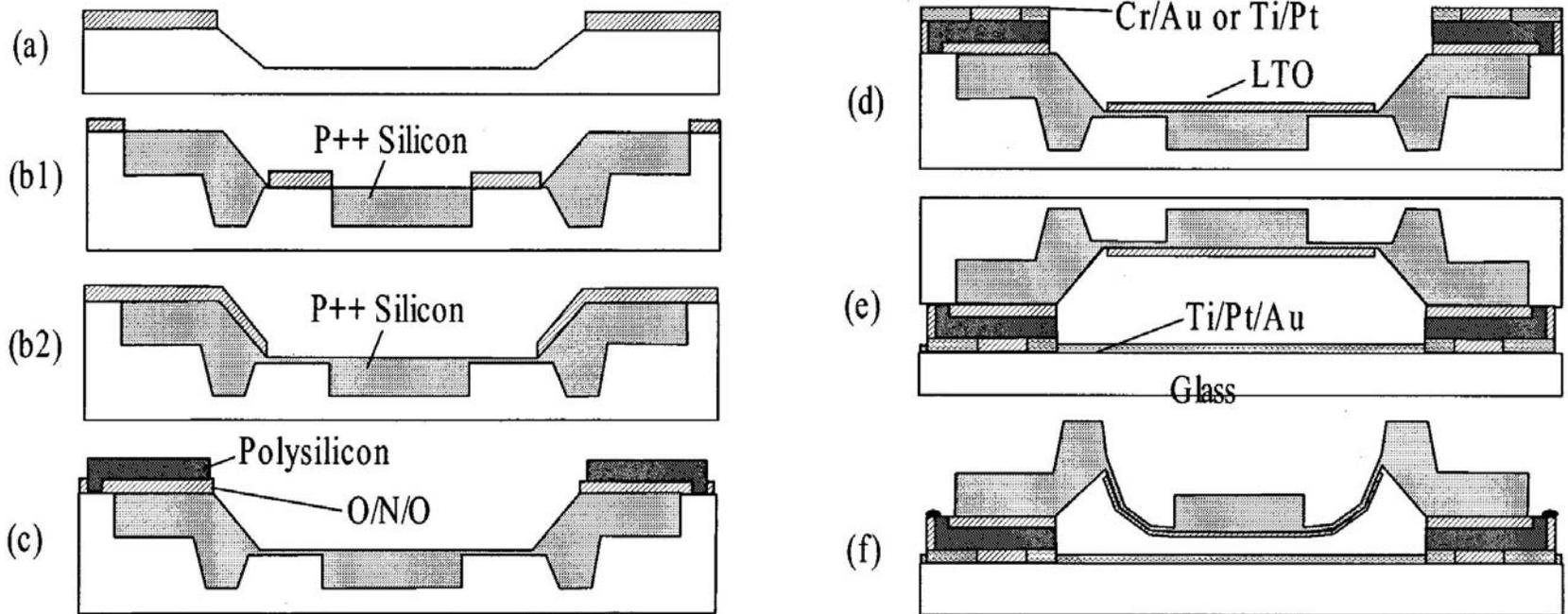


Figure 4 on p. 582 in: Chavan, A. V., and K. D. Wise. "Batch-Processed, Vacuum-Sealed Capacitive Pressure Sensors." *Journal of Microelectromechanical Systems* 10, no. 4 (December 2001): 580-588. © 2001 IEEE.

# Vacuum sealing by fusion bonding

- > An ultrasonic transducer (a microphone, essentially) sealed by silicon fusion bonding
- > Contact in vacuum; risk of outgassing on anneal

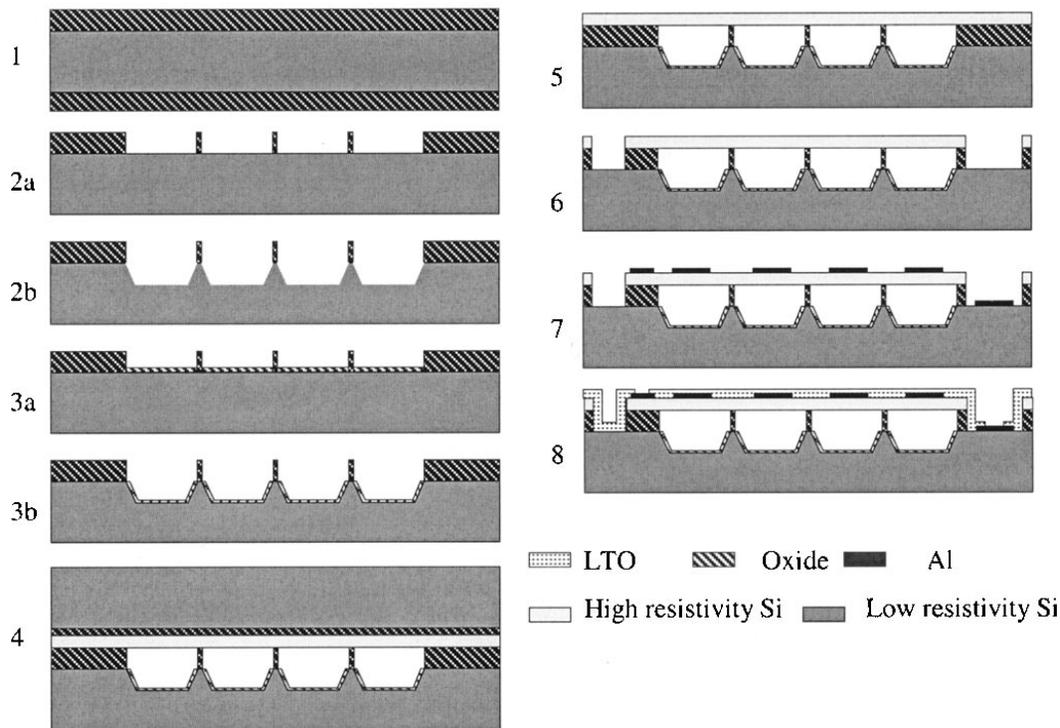


Figure 1 on p. 130 in Huang, Y., A. S. Ergun, E. Haeggstrom, M. H. Badi, and B. T. Khuri-Yakub. "Fabricating Capacitive Micromachined Ultrasonic Transducers with Wafer-bonding Technology." *Journal of Microelectromechanical Systems* 12, no. 2 (April 2003): 128-137. © 2003 IEEE.

# Vacuum sealing by film deposition

- > An ultrasonic transducer sealed by a deposited film
- > Using the stringer effect for a good cause
- > Could worry about outgassing

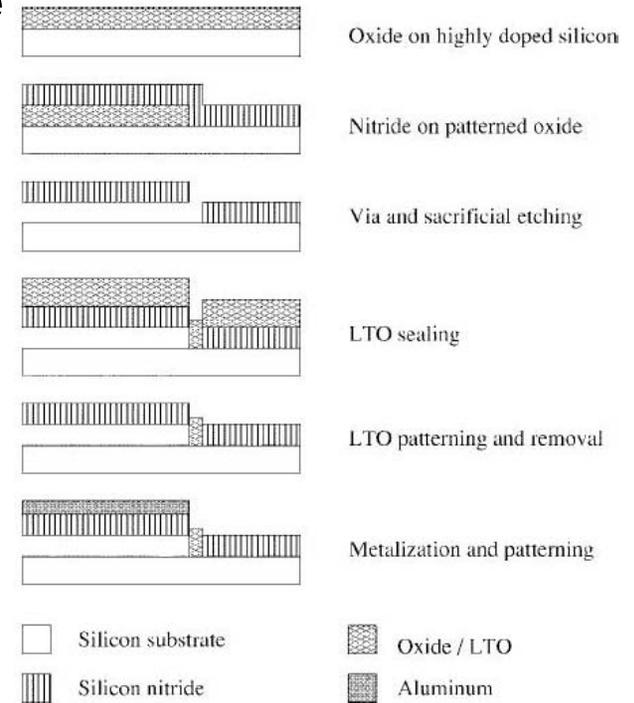
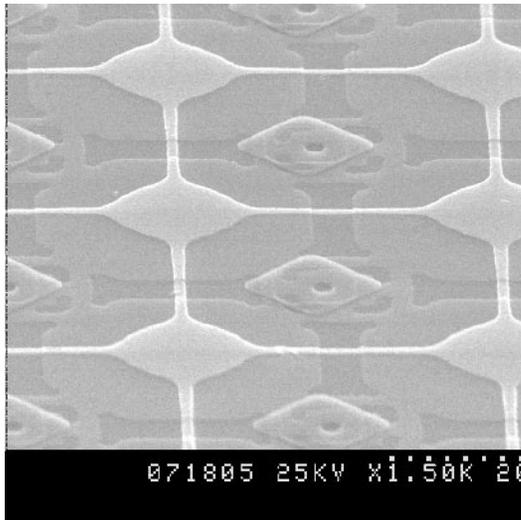


Figure 16 on p. 106 in Jin, X., I. Ladabaum, F. L. Degertekin, S. Calmes, and B. T. Khuri-Yakub. "Fabrication and Characterization of Surface Micromachined Capacitive Ultrasonic Immersion Transducers." *Journal of Microelectromechanical Systems* 8, no. 1 (March 1999): 100-114. © 1999 IEEE.

Figure 2 on p. 101 in Jin, X., I. Ladabaum, F. L. Degertekin, S. Calmes, and B. T. Khuri-Yakub. "Fabrication and Characterization of Surface Micromachined Capacitive Ultrasonic Immersion Transducers." *Journal of Microelectromechanical Systems* 8, no. 1 (March 1999): 100-114. © 1999 IEEE.

# Resonator with thin film vacuum packaging

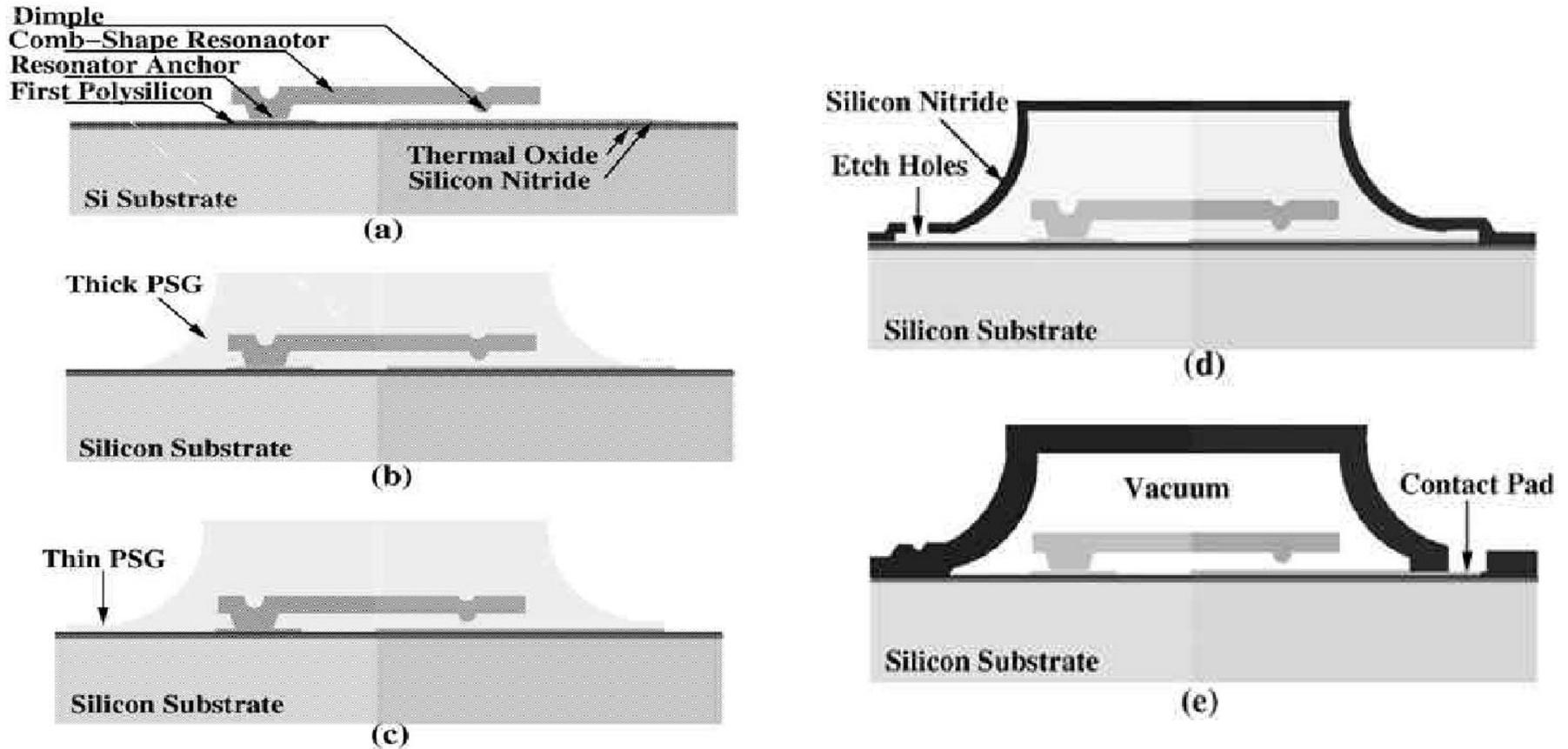


Figure 10 on p. 290 in Lin, L., R. T. Howe, and A. P. Pisano. "Microelectromechanical Filters for Signal Processing." *Journal of Microelectromechanical Systems* 7, no. 3 (September 1998): 286-294. © 1998 IEEE.

# Resonator with thin film vacuum packaging

---

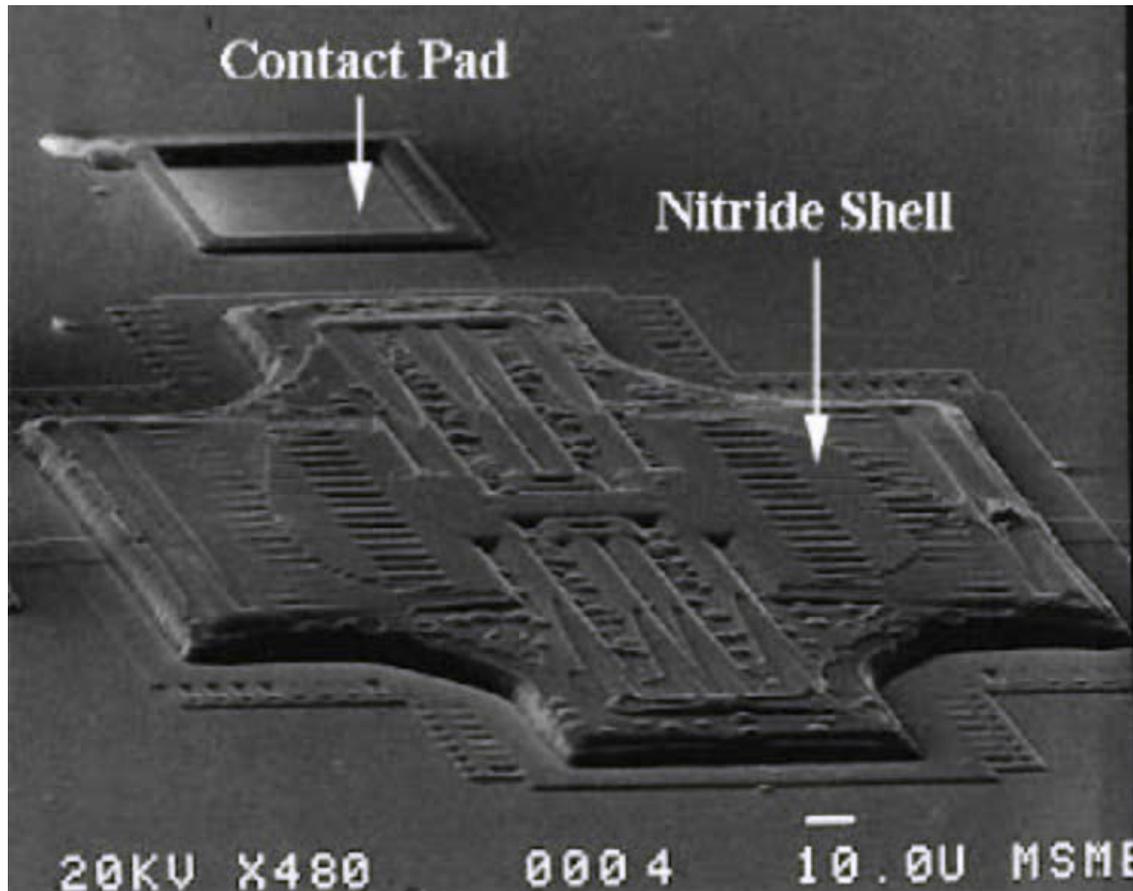


Figure 11 on p. 291 in Lin, L., R. T. Howe, and A. P. Pisano. "Microelectromechanical Filters for Signal Processing." *Journal of Microelectromechanical Systems* 7, no. 3 (September 1998): 286-294. © 1998 IEEE.

# Isolation from the environment

---

- > **Example: an automotive pressure sensor**
  - **The membrane must be able to feel the pressure**
  - **But, the environment is not inert**
  - **Solution: coat the business part to protect it while not compromising the functionality**
  
- > **Example: bioMEMS, especially in the body**
  - **Biocompatible but functional**
  
- > **Parylene is useful here**
  - **Conformal material, deposition near room temperature**
  - **Minimal structural impact**
  - **Resistant to water, many organic solvents, weak acids/bases, salt, fuel... but it is not invulnerable.**

# Hermetic packaging

---

- > **Moisture is bad and can lead to corrosion in the most benign of circumstances**
  - > **Electronics and MEMS often last much longer and are more reliable if moisture is kept out**
  - > **Definition of hermetic: “prevents the diffusion of helium”, with a definition for the maximum allowable helium leak rate**
    - **Perfect hermeticity does not exist in practice**
  - > **Working definition of hermetic: “keeps the moisture out”**
  - > **Good material choices: silicon, metal, ceramic, thick glass (mm thickness or above)**
  - > **Bad material choices: plastics, organic materials**
  - > **All connectors must also be hermetically sealed**
-

# Permeability chart

---

Image removed due to copyright restrictions.

# Considerations when selecting packaging

---

- > **First, everything that you need to think about in designing the device itself**
- > **Electrical parasitics**
- > **Stress: will your package squeeze your device and change its characteristics?**
- > **Will you be able to calibrate and test your device? When and how? All significant package-induced variations must occur before that point, or else be accounted for in advance.**
- > **Other concerns: fragility, range of temperature operation and CTE, etc.**

# Outline

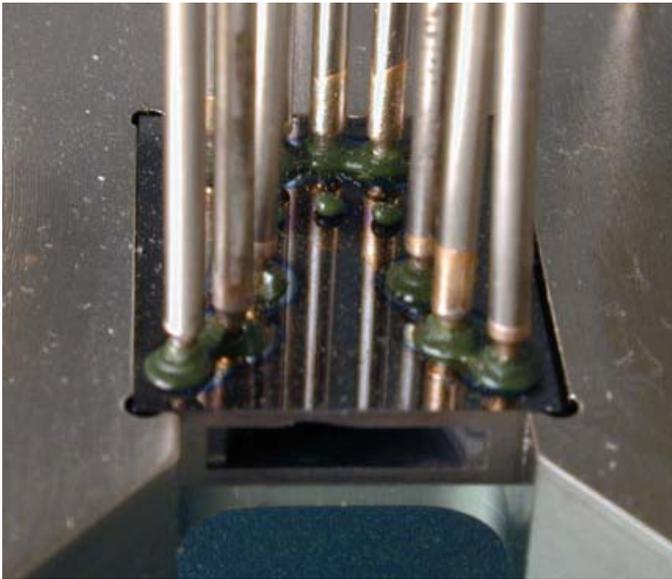
---

- > **Evolution of the packaging dilemma**
- > **How to approach the challenge of getting a working system, including:**
  - **Packaging**
  - **Partitioning**
  - **Test**
  - **Calibration**
- > **Some common tools and considerations**
- > **Examples**

# Lab-scale packaging: micro rocket

---

- > “If I’m just trying to get a degree, and I don’t plan on selling this device, do I still have to design the package with the device?”
- > YES!!! (You want the degree, right?)



Courtesy of Adam London. Used with permission.



Courtesy of Adam London. Used with permission.

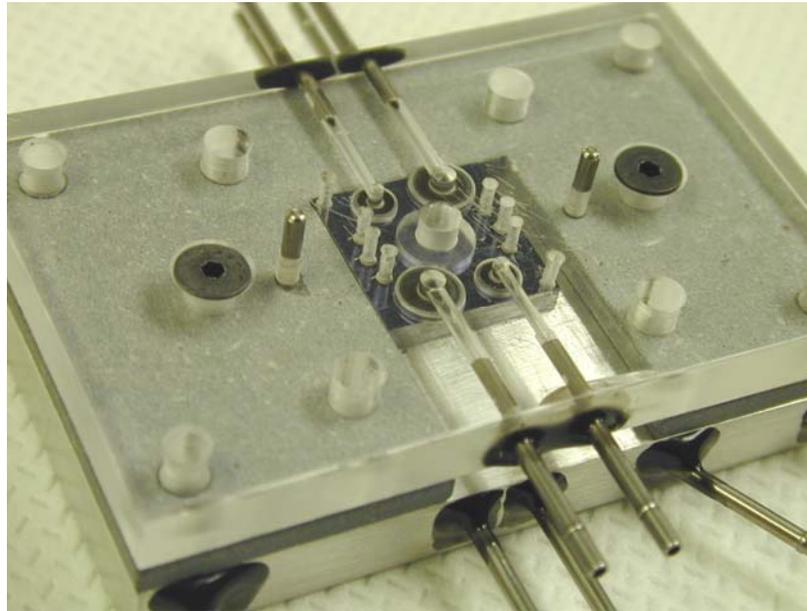
**Source: Adam London, MIT.**

---

# Lab-scale packaging: micro turbine

---

- > Micro turbine device, with fluidic and electrical connections
- > Fluid connections: seal acrylic plate to die via o-rings
- > Questions to think about BEFORE sending out the masks: will the pressure distort the die? Is there room for the o-rings?



# Pressure Sensor Case Study

---

- > **A Motorola manifold-absolute-pressure (MAP) sensor**
- > **Silicon micromachined diaphragm with piezoresistive sensing**

Image removed due to copyright restrictions.  
Motorola manifold absolute pressure sensor.

# Device and Package Concept

- > **Monolithic pressure sensor with circuitry in a custom bipolar process mounted on silicon (\$\$\$) support mounted in plastic package**

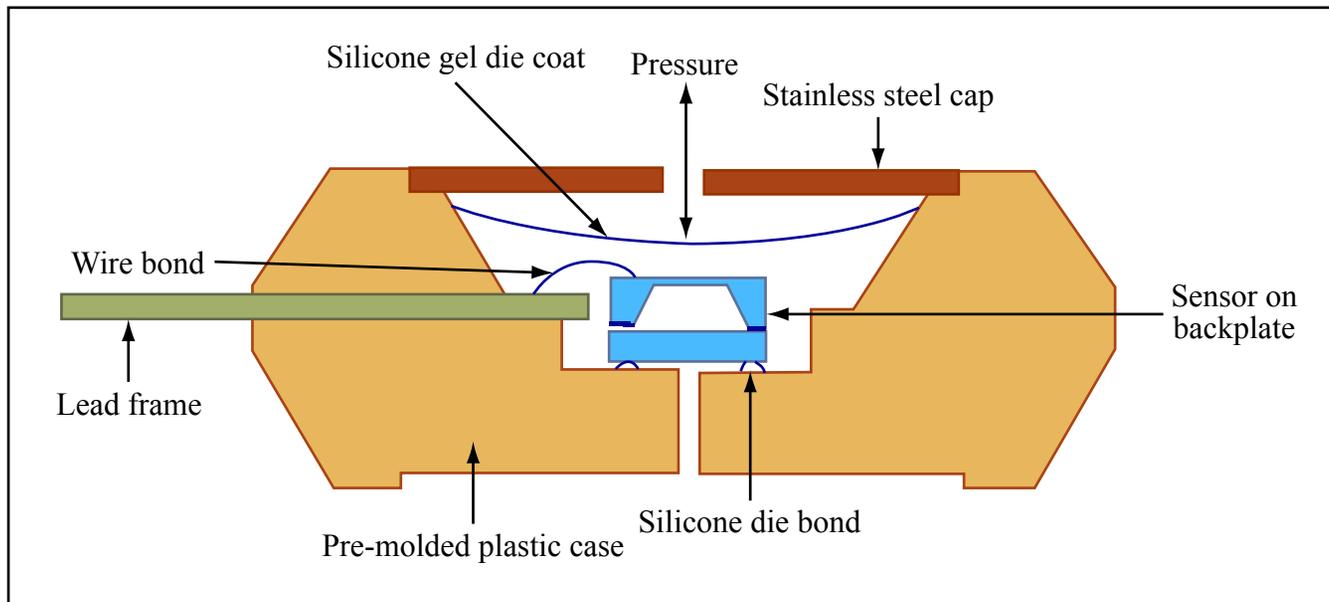


Image by MIT OpenCourseWare.

Adapted from Motorola. *Sensor Device Data/Handbook*. 4th ed. Phoenix, AZ: Motorola, Inc., 1998.

# The Arguments for Monolithic

---

- > **Smaller overall system**
- > **More reliable interconnect**
- > **Solves a customer's problem:**
  - **Does away with a circuit board**
  - **Therefore, may be a cheaper total solution for the customer even if the integrated sensor by itself is more expensive than the hybrid sensor**
- > **It's a business decision....**

# Define Interfaces

---

- > **Electrical interface: how many pins?**
  - The sensor needs only three pins
- > **Mechanical interface: a stainless steel lid on the package**
- > **When to calibrate? Before or after packaging?**
  - Things to consider
    - » Package-induced stress
    - » Gel-seal induced shift in calibration
- > **The decision: Calibrate after bonding into the package, but before the gel-seal.**
  - Cost: **EXTRA PINS ON THE PACKAGE**

# Wafer-level packaging

- > Can't use fusion bonding (circuitry can't stand it)
- > What about anodic bonding?
- > Bonding to silicon backplane using a glass-frit bond (more forgiving of deviations from wafer flatness)
- > Firing temperature between 450 and 500 C.
- > Must be void free and more pure than standard glass frits

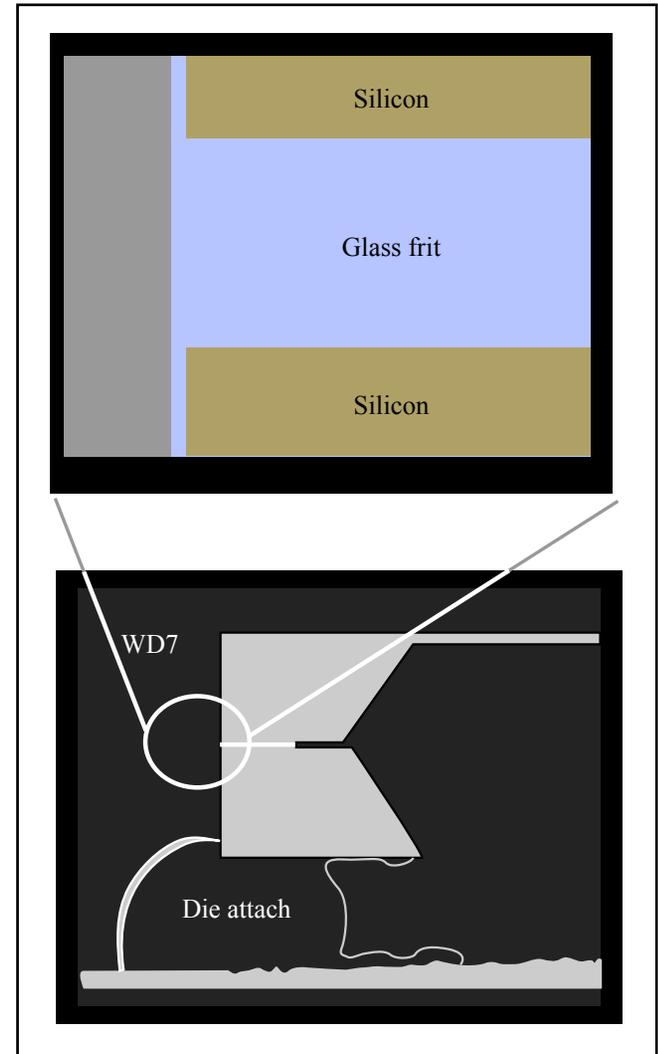


Image by MIT OpenCourseWare.

# Details and headaches

---

- > **Package material and molding process: avoiding leaks**
- > **Die attach**
  - **Originally used RTV (room-temperature vulcanized) silicone adhesives**
  - **Now use a gel-like silicone or fluorosilicone that requires 150 C cure (rubbery material transfers low stress to the chip)**
  - **Biggest problem: batch to batch variation of the die-attach material**
- > **Wire bonding**
  - **With the chip sitting on a gel base, how can you wire bond to it?**
  - **Heat transfer through the gel is poor**
  - **Mechanical support is soft**
  - **Motorola developed custom tooling to apply heat directly to the chip during wire bonding**

# More details and headaches

---

## > Final gel encapsulant

- Must wire bond before trimming, but cannot put final gel coat on until after trimming
- Gel does produce a small shift in response
- Calibration targets must be pre-distorted to anticipate the effect of the gel coat
- Batch to batch variations in gel materials can then create problems

Image removed due to copyright restrictions.

## > Next level assembly: keeping customers happy

- Market fragmentation
- Different customers want different next-level assemblies (Ford doesn't want a Chrysler package)

# Example: a newer capping technology

---

## > Disclaimer:

- This is not a sales pitch. This particular technology is described here simply because it is well-described in the literature. Flexible packaging techniques are of wide interest.

## > Concept: bulk-micromachined silicon caps with integrated interconnects, assembled onto dies at the wafer-scale

## > Electrical connections and hermetic package seal made by flip-chip solder bonding and through-cap interconnects

## > Small overall package sizes possible

## > Clean (no particles from ceramic components), CTE matched to minimize damage and package-device interaction

## > Reference: Elger et al., presented at IMAPS 04, cap technology by Hymite

---

# Application for this example

---

- > **MEMS switch for in vivo use, to be switched by an external magnetic field**

Image removed due to copyright restrictions.

Image removed due to copyright restrictions.

Image removed due to copyright restrictions.

# Details

---

- > **Caps made by standard KOH/electroplating bulk micromachining process**
    - **SOI substrate, KOH etched from both sides**
  - > **Including interconnects in device would lower yield and affect device process flow**
  - > **Through-cap interconnects permit flip-chip bonding to device and to outside world with minimal disturbance to device process**
  - > **Silicon caps can be cleaned with chips before assembly to minimize unwanted material in sealed-cavity**
  - > **Moderately low melting solder with no flux (no organic contamination)**
  - > **Pick and place assembly, or wafer to wafer transfer; heat in the pick and place tool to prevent caps from sliding**
-

# Bottom line

---

- > People are actively trying to create and sell techniques like this that can package a greater (though still not infinite) set of MEMS devices with a single process and vendor**
- > This may make the life of the MEMS designer easier, permit smaller packages, and (hopefully some day) smooth the trip to market for some MEMS devices**
- > But there is still no universal solution: what if you need optical access, fluidic access?**
- > And you still have to design the device and the packaging process together, even as the number and convenience of available tools increases**

# Where to learn more

---

- > **Nadim Maluf, “An Introduction to Microelectromechanical Systems Engineering”, Artech House, 2000.**
- > **Handbooks of microelectronics packaging, such as:**
  - **R.R. Tummala and E.J. Rymaszewski (eds.), Microelectronics Packaging Handbook, Reinhold, 1989.**